Applicant(s)/Patent Under Reexamination 10/735,096 TSUN ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 GEORGE L. OPIE 2194

Application/Control No.

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,321,835	06-1994	Tanaka et al.	718/101
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